

Customer No.: 31561
Application No.: 10/710,670
Docket No.: 12778-US-PA

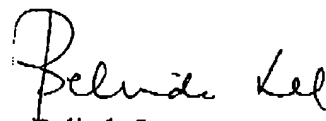
REMARKS

Applicants would like to elect Group I, claims 1-7, drawn to an auto-recovery wafer testing method, classified in class 438, subclass 14. Please cancel Group II, claims 8-11, drawn to an auto-recovery wafer testing apparatus, classified in class 324, subclass 765, without waiver, prejudice or disclaimer.

If the Examiner believes that a telephone conference would expedite the examination of the above-identified patent application, the Examiner is invited to call the undersigned.

Respectfully submitted,

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